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Applicant: Aleksey Yurievich KOLESNYCHENKO, et al.

Appln. No.: 10/823,777

Filing Date: April 14, 2004

Examiner: GUTIERREZ, Kevin C. Group Art Unit: 2851

Date: November 7, 2007

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	ZZR				Enclose	No
	AAAR					

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	GGGGR					
	HHHHR					
	IIIIIR					
	JJJJR					
	KKKKR					
	LLLLR					
	MMMMR					
	NNNNR					
	OOOOR					
	PPPPR					

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				Enclosed	No
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